# International Rectifier

### HEXFET® Power MOSFET

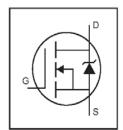
- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- · Lead-Free

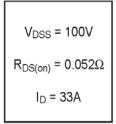
#### Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve the lowest possible on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient device for use in a wide variety of applications.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole.

## IRFP140NPbF







### **Absolute Maximum Ratings**

	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, VGS @ 10VS	33	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V®	23	A
I <sub>DM</sub>	Pulsed Drain Current ①⑤	110	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	140	W
	Linear Derating Factor	0.91	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	±20	V
Eas	Single Pulse Avalanche Energy ②⑤	300	mJ
I <sub>AR</sub>	Avalanche Current ①	16	А
E <sub>AR</sub>	Repetitive Avalanche Energy®	14	mJ
d∨/dt	Peak Diode Recovery dv/dt ③⑤	5.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw.	10 lbf•in (1.1N•m)	

### Thermal Resistance

	Parameter	Min.	Тур.	Max.	Units
Reuc	Junction-to-Case			1.1	
R <sub>0CS</sub>	Case-to-Sink, Flat, Greased Surface		0.24		°C/W
ReJA	Junction-to-Ambient			40	

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### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	• • •					• ,
	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	100			٧	$V_{GS} = 0V$ , $I_D = 250 \mu A$
ΔV <sub>(BR)DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient		0.11		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA <sup>©</sup>
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	_		0.052	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 16A ⊕
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
<b>g</b> fs	Forward Transconductance	11			S	V <sub>DS</sub> = 50V, I <sub>D</sub> = 16A <sup>⑤</sup>
ı	Drain-to-Source Leakage Current			25		V <sub>DS</sub> = 100V, V <sub>GS</sub> = 0V
I <sub>DSS</sub>	Diani-to-Source Leakage Current			250	μA	V <sub>DS</sub> = 80V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 150°C
1	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	IIA I	V <sub>GS</sub> = -20V
Qg	Total Gate Charge			94		I <sub>D</sub> = 16A
Qgs	Gate-to-Source Charge			15	nC	V <sub>DS</sub> = 80V
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge			43		V <sub>GS</sub> = 10V, See Fig. 6 and 13 ⊕ ⑤
t <sub>d(on)</sub>	Turn-On Delay Time		8.2			V <sub>DD</sub> = 50V
tr	Rise Time		39			I <sub>D</sub> = 16A
$t_{\text{d(off)}}$	Turn-Off Delay Time		44		ns	$R_{G} = 5.1\Omega$
t <sub>f</sub>	Fall Time		33			$R_D = 3.0\Omega$ , See Fig. 10 $\oplus$ $\bigcirc$
L <sub>D</sub>	Internal Drain Inductance					Between lead,
<b>-</b> D	internal Drain inductance		5.0			6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		13		nH	from package
						and center of die contact
C <sub>iss</sub>	Input Capacitance		1400			V <sub>GS</sub> = 0V
Coss	Output Capacitance		330		pF	V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance		170		1 i	f = 1.0MHz, See Fig. 5⑤

### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions	
Is	Continuous Source Current			33		MOSFET symbol	
	(Body Diode)		_	33	Α	showing the	
I <sub>SM</sub>	Pulsed Source Current			110	'`	integral reverse	
	(Body Diode) ①③	_ i _ i				p-n junction diode.	s
V <sub>SD</sub>	Diode Forward Voltage			1.3	V	$T_{J} = 25^{\circ}C$ , $I_{S} = 16A$ , $V_{GS} = 0V \oplus$	
t <sub>rr</sub>	Reverse Recovery Time	_	170	250	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 16A	
Qrr	Reverse RecoveryCharge		1.1	1.6	μC	di/dt = 100A/µs ⊕⑤	

#### Notes:

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- ${\Large \textcircled{1}}$  Repetitive rating; pulse width limited by max, junction temperature. ( See fig. 11 )
- $\ \ \, \mathbb{O} \ \ \, V_{DD}$  = 25V, starting  $\ \ \, T_J$  = 25°C, L = 2.0mH  $\ \ \, R_G$  = 25 $\Omega$ ,  $\ \ \, I_{AS}$  = 16A. (See Figure 12)
- $\ \Im \ I_{\text{SD}} \leq 16 A, \ di/dt \leq 210 A/\mu s, \ V_{\text{DD}} \leq V_{(\text{BR})\text{DSS}}, \ T_{\text{J}} \leq 175 ^{\circ}\text{C}$
- 1 Pulse width  $\leq 300 \mu s$ ; duty cycle  $\leq 2\%$ .
- © Uses IRF540N data and test conditions.

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## IRFP140NPbF

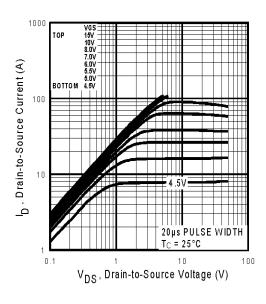


Fig 1. Typical Output Characteristics

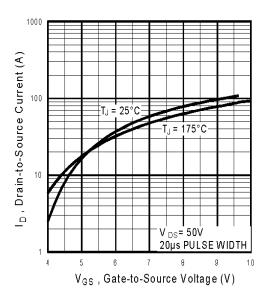


Fig 3. Typical Transfer Characteristics

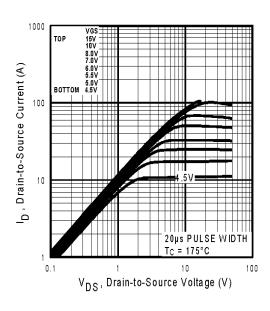


Fig 2. Typical Output Characteristics

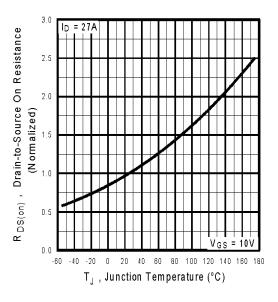
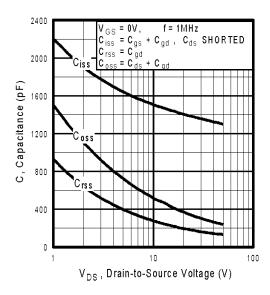
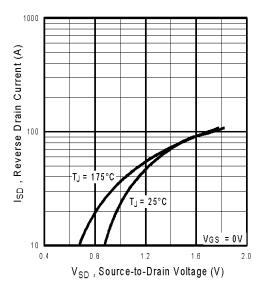


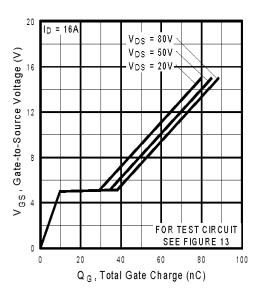
Fig 4. Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

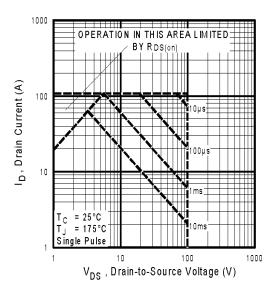


Fig 8. Maximum Safe Operating Area

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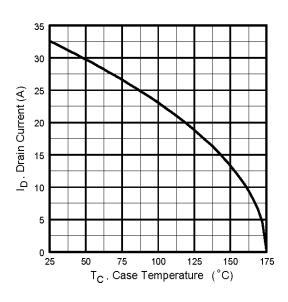


Fig 9. Maximum Drain Current Vs.
Case Temperature

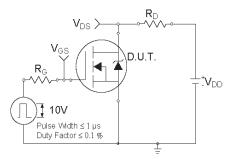


Fig 10a. Switching Time Test Circuit

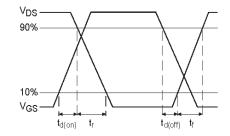


Fig 10b. Switching Time Waveforms

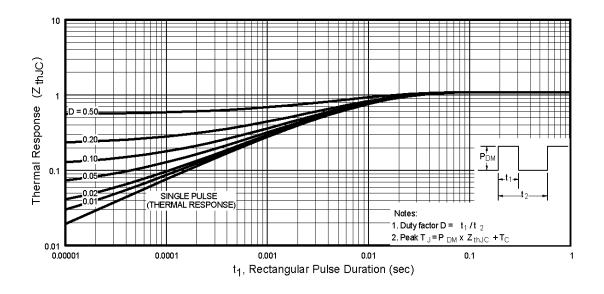


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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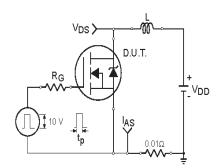


Fig 12a. Unclamped Inductive Test Circuit

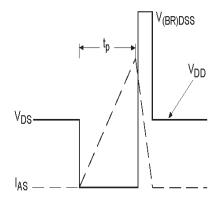
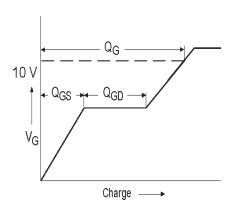
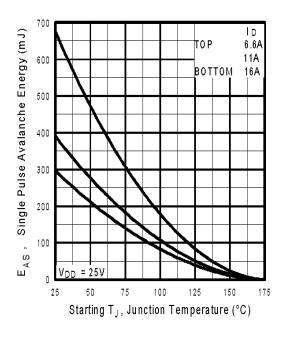


Fig 12b. Unclamped Inductive Waveforms



**Fig 13a.** Basic Gate Charge Waveform 6



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

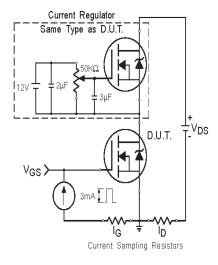
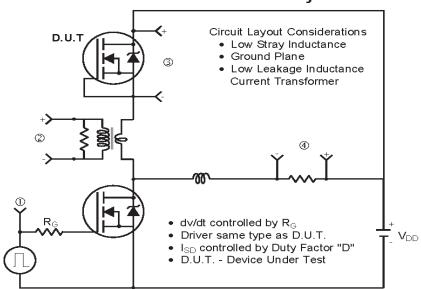


Fig 13b. Gate Charge Test Circuit www.irf.com

### Peak Diode Recovery dv/dt Test Circuit



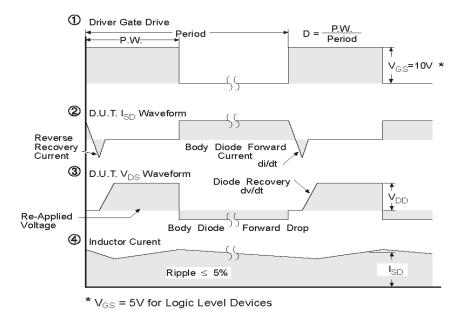
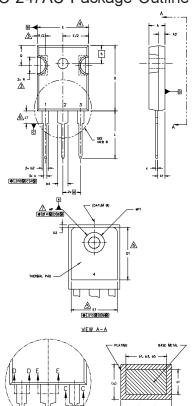


Fig 14. For N-Channel HEXFETS

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### TO-247AC Package Outline Dimensions are shown in millimeters (inches)



<u> </u>	INTOUR OF	SLOT OPTI	ONAL.			
						) FLASH SHALL NOT EXCEED .005" (0.127) OUTERMOST EXTREMES OF THE PLASTIC BODY.
<u>√5</u> ™	FRMAL PAI	CONTOUR	OPTIONAL	WITHIN DIM	FNISONS	D1 & F1.
			LED IN L1.			
				IGLE OF 1.	5 ' TO TH	E TOP OF THE PART WITH A MAXIMUM HOLE
l Div	AMETER OF	.154" [3.9	1].			
8. OL	JTLINE CON	FORMS TO	JEDEC OUTL	INE TO-24	17 WITH 1	THE EXCEPTION OF DIMENSION C.
		DIMEN	ISIONS			
SYMBOL	INC	HES	MILLIM	ETERS	1	
ıİ	MIN.	MAX.	MIN.	MAX.	NOTES	
A	.183	.209	4.65	5.31		LEAD ASSIGNMENTS
A1	.087	.102	2.21	2.59		
A2	.059	.098	1,50	2.49		HEXFET
b	.039	.055	0.99	1.40		next et
ь1	.039	.053	0.99	1.35		1,- GATE
ь2	.065	.094	1.65	2.39		2 DRAIN
b3	.065	.092	1,65	2.37		3 SOURCE
b4	.102	.135	2.59	3.43		4,- DRAIN
b5	.102	.133	2.59	3.38		
C	.015	.034	0.38	0.86		100T. 0 D40V
c1	.015	.030	0.38	0.76	١	IGBTs, CoPACK
D D1	.776	.815	19.71	20.70	5	1 GATE
D2	.515 .020	- 070	13.08		) >	2,- COLLECTOR
E	.602	,030 ,625	0,51 15,29	0,76 15,87	4	3,- EMITTER
E1	.540	,025	15.72	- 15.67	"	4,- COLLECTOR
e	.215	RSC		BSC	1	
øk i		10	2.		1	
^^	.559	.634	14.20	16.10	1	DIODES
L1	.146	.169	3.71	4.29		1 ANODE/OPEN
N N		3	7.62	BSC	1	2 CATHODE
øP	.140	,144	3.56	3.66	1	3,- ANODE
øP1	-	.275	-	6.98		
0	.209	.224	5.31	5.69		
R	.178	.216	4.52	5.49		
l s [	.217	BSC	5,51	BSC		

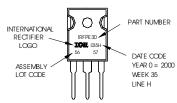
DIMENSIONING AND TOLERANCING PER ASME Y14.5M 1994, DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS]

## TO-247AC Part Marking Information

SECTION C-C, D-D, E-E



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Data and specifications subject to change without notice.



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